

PATENT ABSTRACTS OF JAPAN

(11)Publication number : **60-021440**

(43)Date of publication of application : **02.02.1985**

(51)Int.Cl. **G01N 23/06**

G21C 17/02

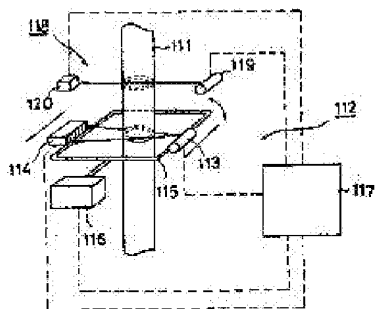
(21)Application number : **58-128920** (71)Applicant : **TOSHIBA CORP**
(22)Date of filing : **15.07.1983** (72)Inventor : **IIZUKA MASARU**

(54) **METHOD FOR MEASURING DISTRIBUTION OF LOCAL VOID RATE**

(57)Abstract:

PURPOSE: To measure the distribution of a local void rate accurately, by measuring a time when projection data is converged to a constant value in advance, and performing the measurement at this timing.

CONSTITUTION: A density meter 118 for X rays or γ rays is arranged so as to hold a pipe 111, in which a sample to be checked flows. A time, when projection data is converged into a constant value, is measured in advance by the density meter 118, and a collecting time of the projection data is determined. Based on the determined collecting time, a CT scanner device 112 is actuated and the measurement is started. Namely, a driving device 116 is controlled by a control device 117, a radiation source 113, which generates X rays or γ rays, and a detector 114 are made to scan, and the distribution of a local void rate in the pipe 111 is measured. Thus the distribution of the local void rate can be measured accurately.



LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]